

SI4482DY-T1-E3-VB Datasheet N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS}	100	V		
R _{DS(on)} V _{GS} = 10 V	32	mΩ		
I _D	9	Α		
Configuration	Single			

SO-8 S 1 8 D S 2 7 D S 3 6 D Top View

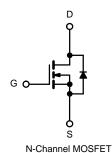
FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Extremely Low Q_{gd} for Switching Losses
- 100 % R_g Tested
- 100 % Avalanche Tested
- Compliant to RoHS Directive 2002/95/EC



APPLICATIONS

· Primary Side Switch



Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	100	V	
Gate-Source Voltage		V _{GS}	± 20	V	
-	T _C = 25 °C		9		
Continuous Drain Current (T _{.1} = 150 °C)	$T_C = 70 ^{\circ}C$	I_	6		
Continuous Diam Current (1) = 150°C)	T _A = 25 °C	l _D	6 ^{b, c}		
	T _A = 70 °C	1	5 ^{b, c}	Α	
Pulsed Drain Current		I _{DM}	40	^	
Continuous Source-Drain Diode Current	T _C = 25 °C		7		
	T _A = 25 °C	Is	3.8 ^{b, c}		
Single Pulse Avalanche Current L = 0.1 m		I _{AS}	30		
Single Pulse Avalanche Energy		E _{AS}	112	mJ	
Maximum Power Dissipation	T _C = 25 °C		14		
	T _C = 70 °C	P_{D}	5	w	
	T _A = 25 °C] 「	4 ^{b, c}	VV	
	T _A = 70 °C	1	2 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stq}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	33	40	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	17	21	0,7		

Notes:

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under steady state conditions is 80 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I - 250 uA		172		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = 250 μA		- 10		IIIV/ C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1.0		3.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current		V _{DS} = 100 V, V _{GS} = 0 V			1	
	IDSS	V _{DS} = 100 V, V _{GS} = 0 V, T _J = 55 °C			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α
Drain Course On State Desistance		$V_{GS} = 10 \text{ V, } I_{D} = 5 \text{ A}$		32		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 5 \text{ A}$		33		mΩ
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 5 A		20		S
Dynamic ^b						
Input Capacitance	C _{iss}			1900		pF
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		150		
Reverse Transfer Capacitance	C _{rss}			50		
Total Cata Charge	Qg	V _{DS} = 75 V, V _{GS} = 10 V, I _D = 5 A		28.5	43	
Total Gate Charge				23	35	nC
Gate-Source Charge	Q_{gs}	$V_{DS} = 75 \text{ V}, V_{GS} = 8 \text{ V}, I_{D} = 5 \text{ A}$		8		nC
Gate-Drain Charge	Q_{gd}			6.5		
Gate Resistance	R_{g}	f = 1 MHz		0.80	1.3	Ω
Turn-on Delay Time	t _{d(on)}			14	21	
Rise Time	t _r	V_{DD} = 50 V, R_L = 10 Ω		12	18	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		22	33	
Fall Time	t _f			6	10	ne
Turn-On Delay Time	t _{d(on)}			16	24	ns
Rise Time	t _r	V_{DD} = 50 V, R_L = 10 Ω		12	18	1
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 8 \text{ V}, R_g = 1 \Omega$		20	30	
Fall Time	t _f			7	12	<u></u>
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			7.7	^
Pulse Diode Forward Current ^a	I _{SM}				50	A
Body Diode Voltage	V _{SD}	I _S = 2.6 A		0.77	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			63	95	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _E = 5 A, dl/dt = 100 A/μs, T _{.1} = 25 °C		110	165	nC
Reverse Recovery Fall Time	t _a	$I_F = 3 \text{ A}$, $UI/UI = 100 \text{ A/}\mu\text{S}$, $I_J = 25 \text{ C}$		49		
Reverse Recovery Rise Time	t _b			14		ns

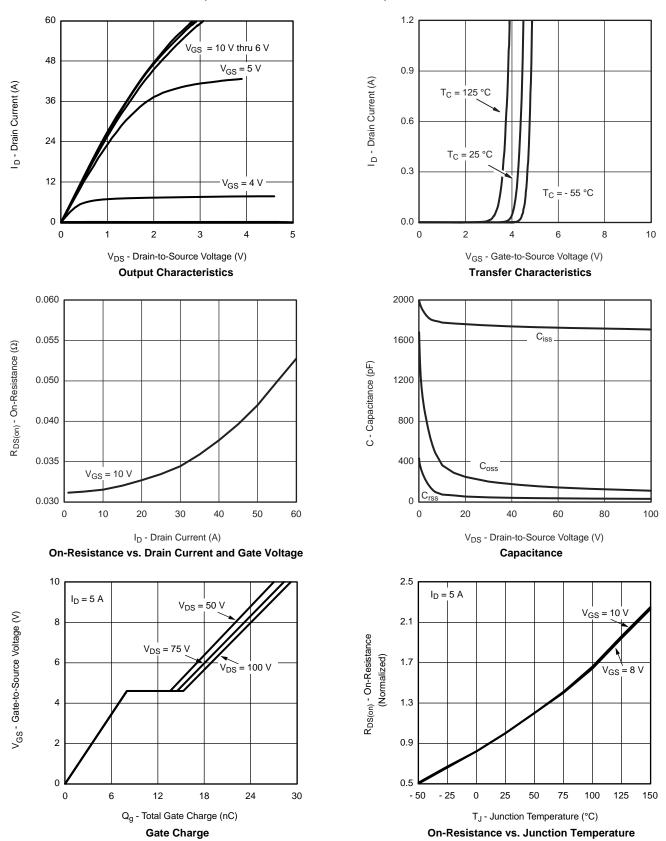
Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

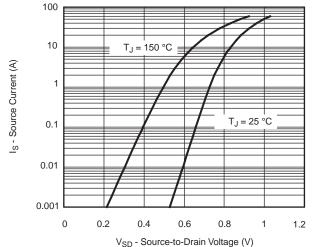
a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$

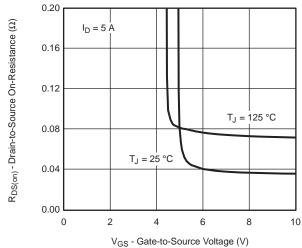
a. Guaranteed by design, not subject to production testing.



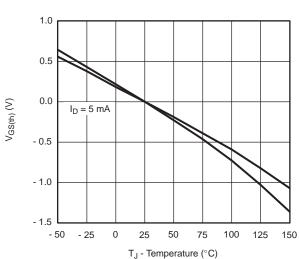




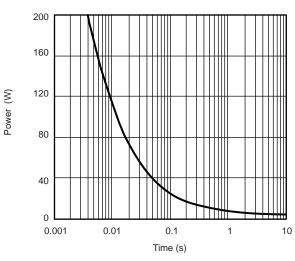




Source-Drain Diode Forward Voltage

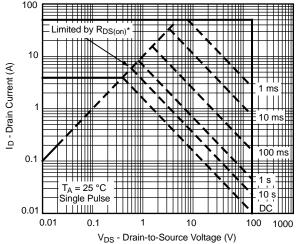


On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

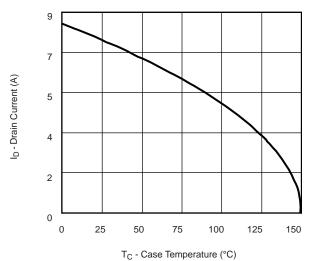
Single Pulse Power, Junction-to-Ambient



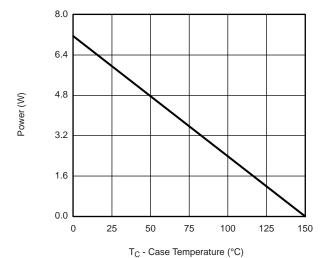
 v_{DS} - Drain-to-Source voltage (V) * v_{GS} > minimum v_{GS} at which $v_{DS(on)}$ is specified

Safe Operating Area, Junction-to-Ambient

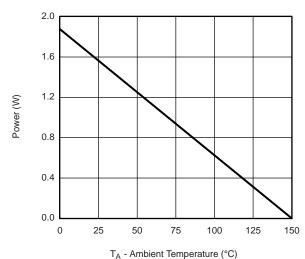




Current Derating*



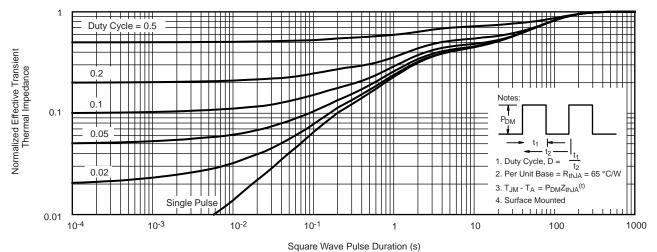
Power, Junction-to-Case



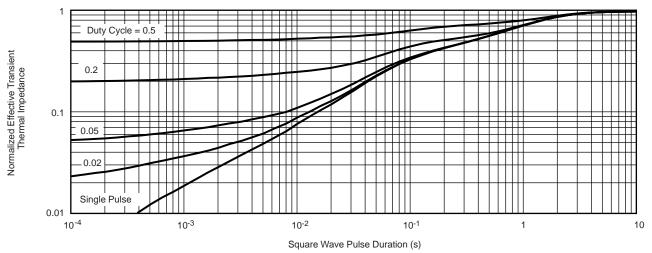
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

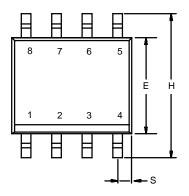


Normalized Thermal Transient Impedance, Junction-to-Foot

服务热线:400-655-8788 6



SOIC (NARROW): 8-LEADJEDEC Part Number: MS-012







	MILLIM	IETERS	INCHES			
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Pay I 11-San-06						

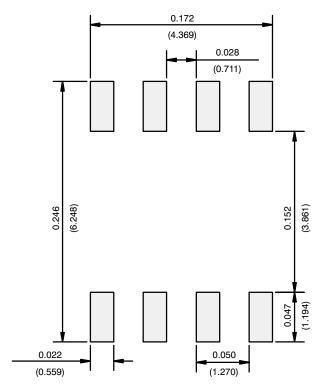
ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



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RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)



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